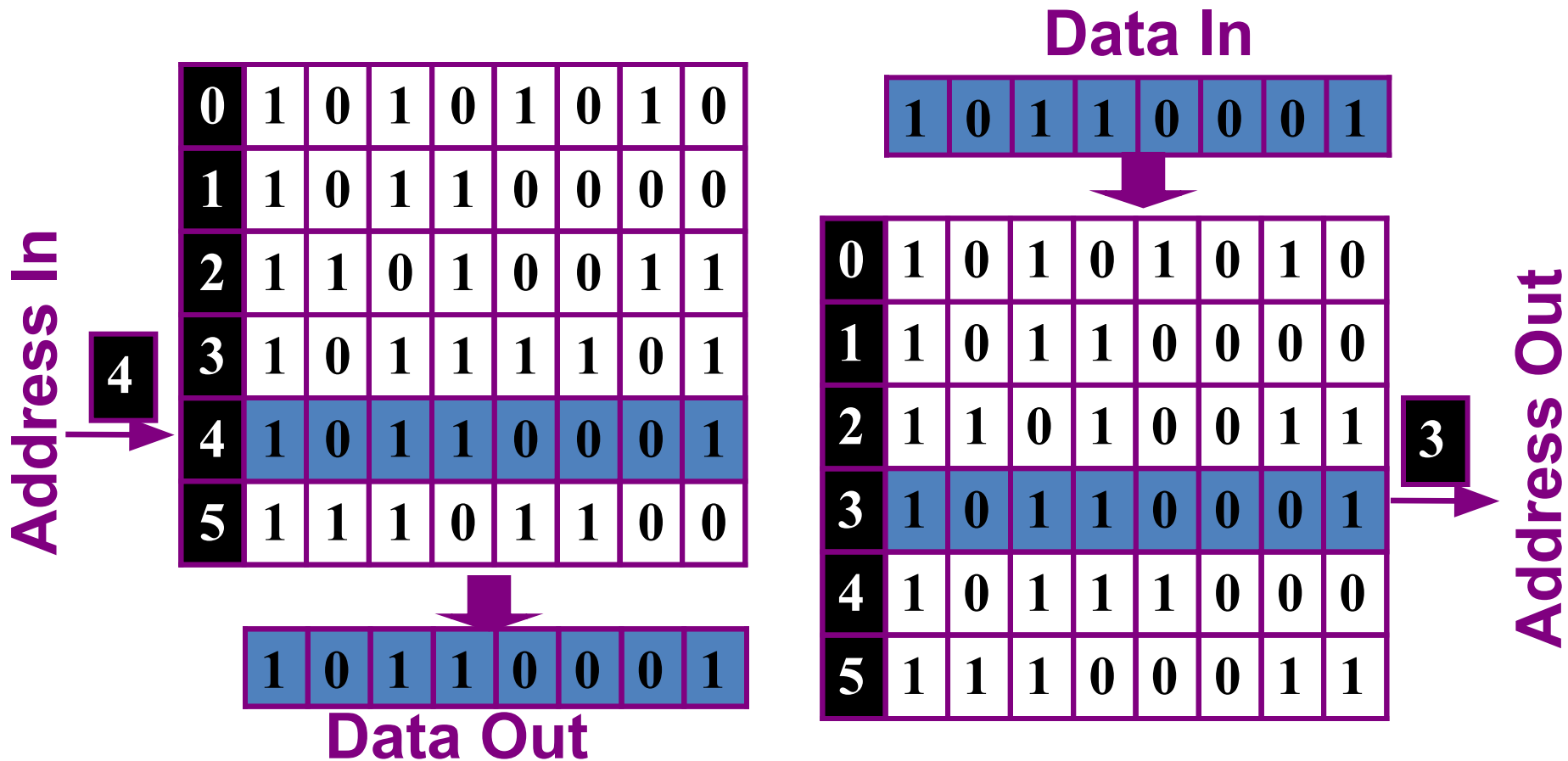


# CAM

- CAM vs. RAM



# CAM

- Ternary CAM (TCAM)

Input Keyword

1	0	1	1	0	X	X	X
---	---	---	---	---	---	---	---



0	1	0	1	0	X	0	1	0	1
1	1	0	1	1	0	1	0	1	Match
2	1	X	0	1	0	0	1	1	
3	1	0	1	1	1	0	0	0	4
4	1	0	1	1	0	0	1	0	Match
5	1	1	1	0	0	X	0	0	

Input Keyword

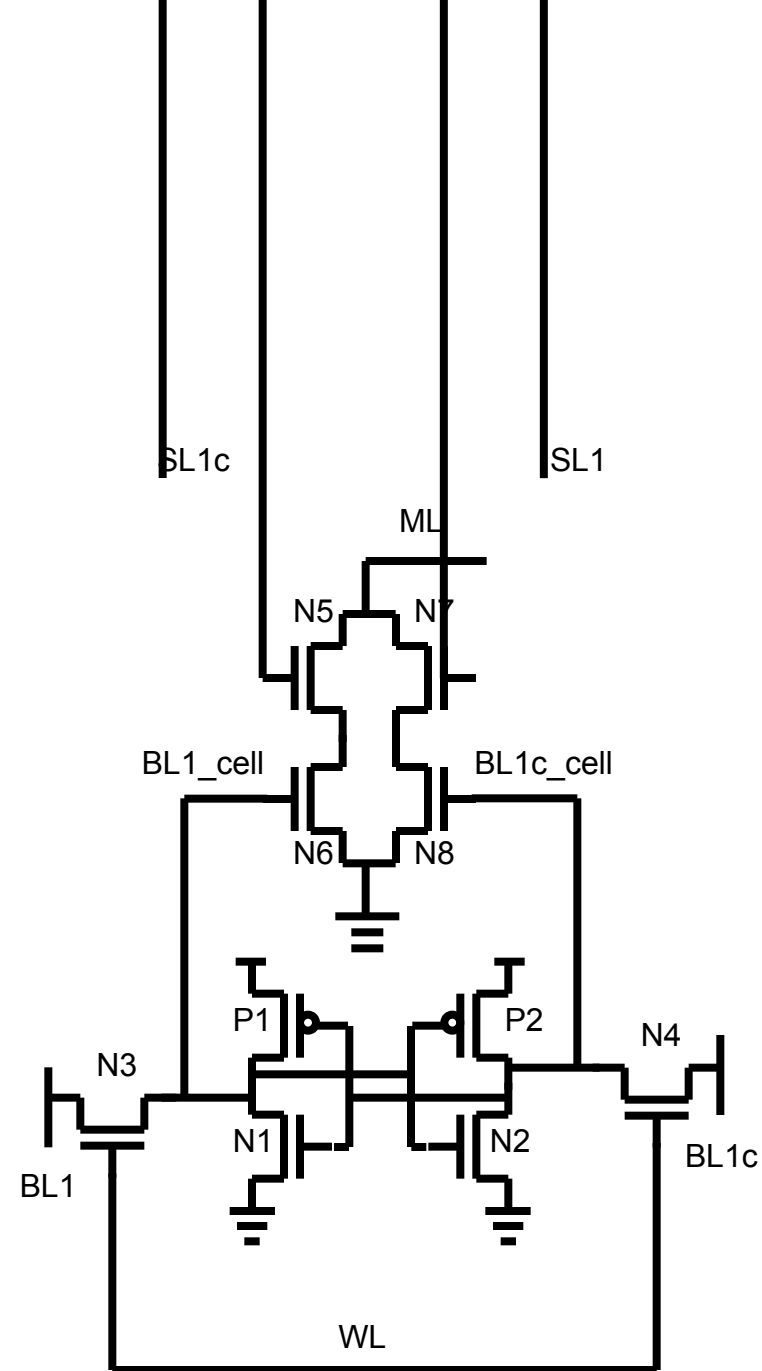
1	0	1	1	0	0	0	1
---	---	---	---	---	---	---	---



0	1	0	1	0	1	0	1	0	1
1	1	0	1	1	0	0	0	X	Match
2	1	1	0	1	0	0	X	X	
3	1	0	1	1	1	X	X	X	4
4	1	0	1	1	X	X	X	X	Match
5	1	1	1	X	X	X	X	X	

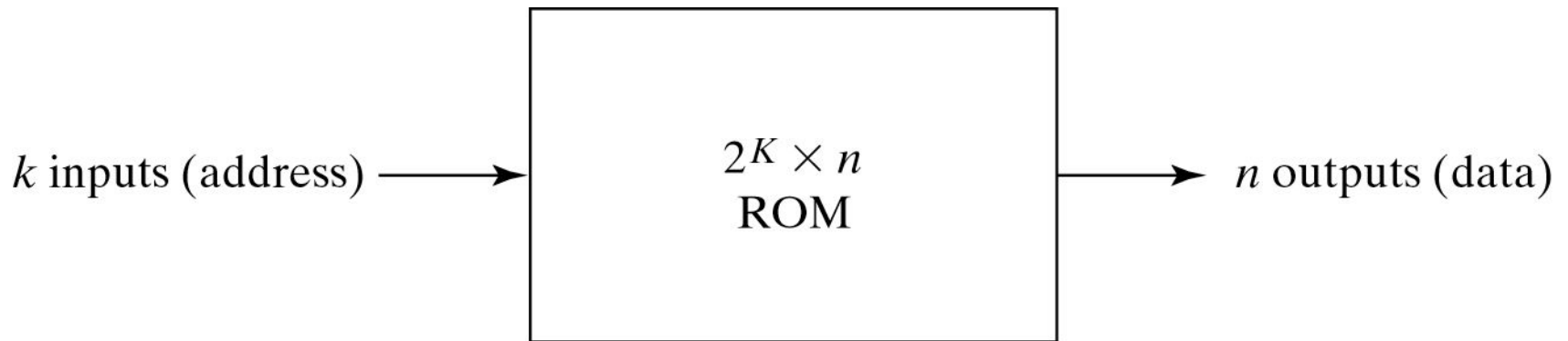
# CAM

- Binary CAM Cell
  - ML pre-charged to  $V_{DD}$
  - Match: ML remains at  $V_{DD}$
  - Mismatch: ML discharges



# Read-Only Memory

- A block diagram of a ROM is shown below. It consists of  $k$  address inputs and  $n$  data outputs.
- The number of words in a ROM is determined from the fact that  $k$  address input lines are needed to specify  $2^k$  words.



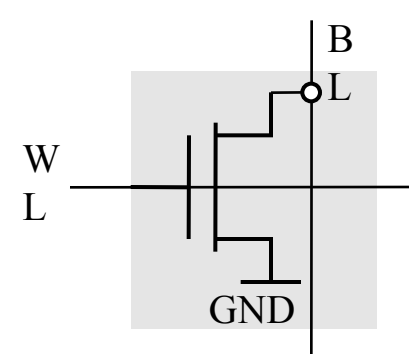
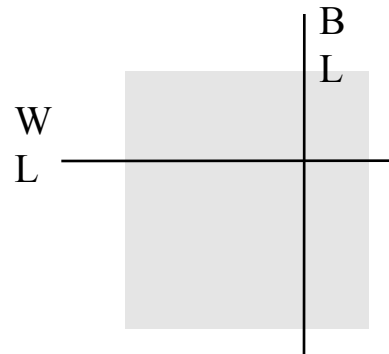
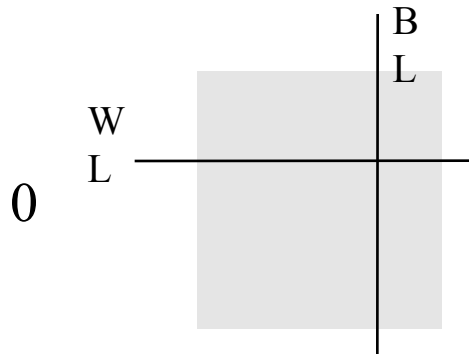
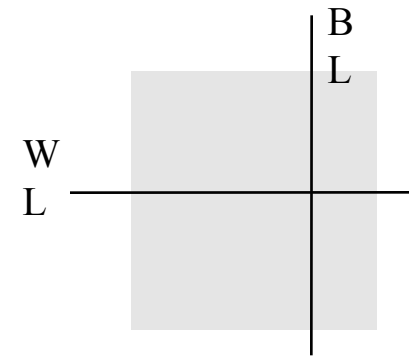
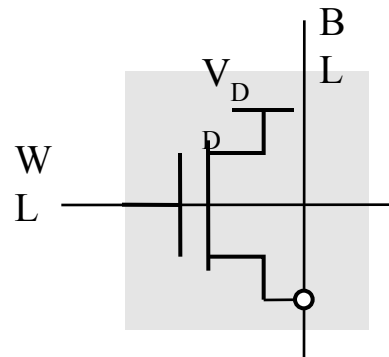
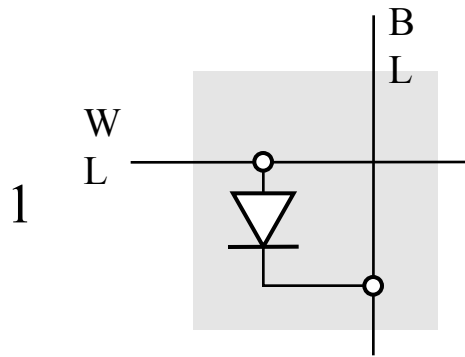
ROM Block diagram  $2^k \times n$  Module

# Read-Only Memory Cells

Bit line (BL) is **resistively clamped to the ground**, so its default value is 0

Diode disadvantage – no electrical isolation between bit and word lines

BL is **resistively clamped to VDD**, so its default value is 1



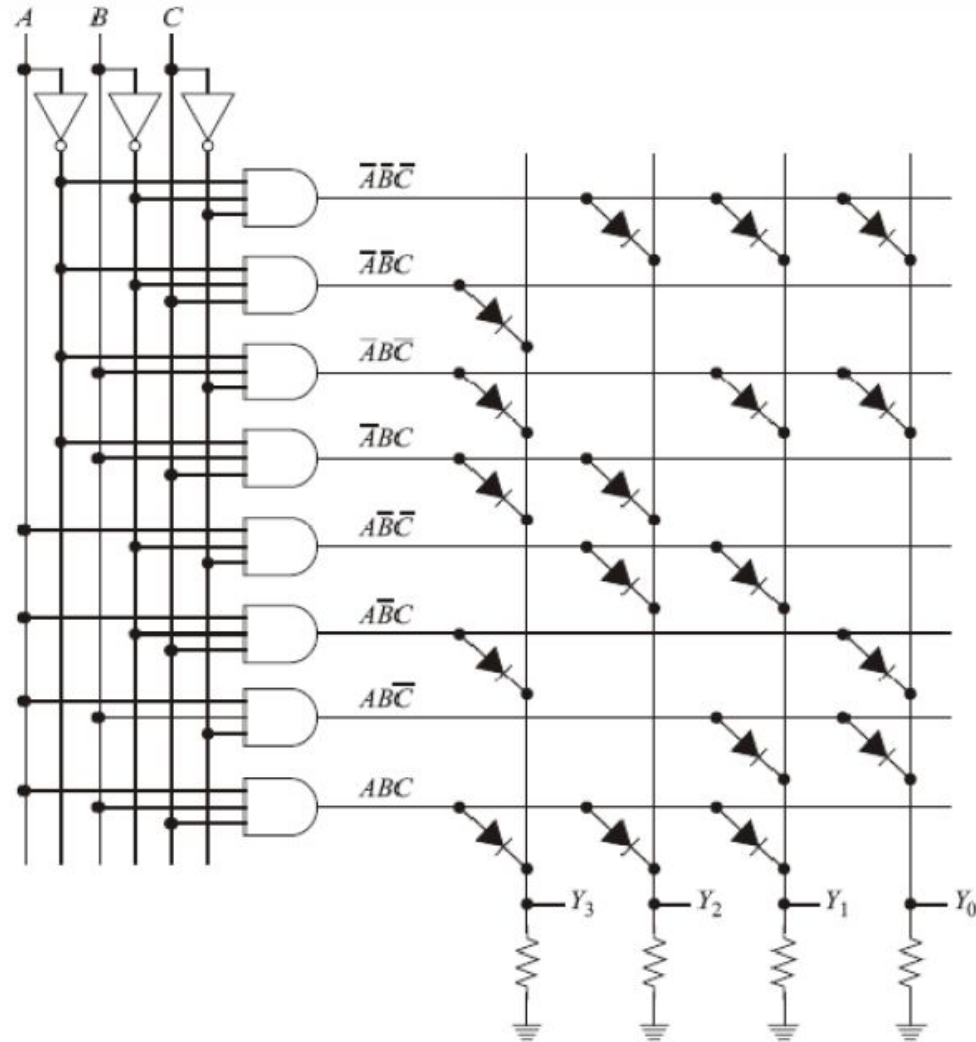
Diode ROM

MOS ROM 1

MOS ROM 2

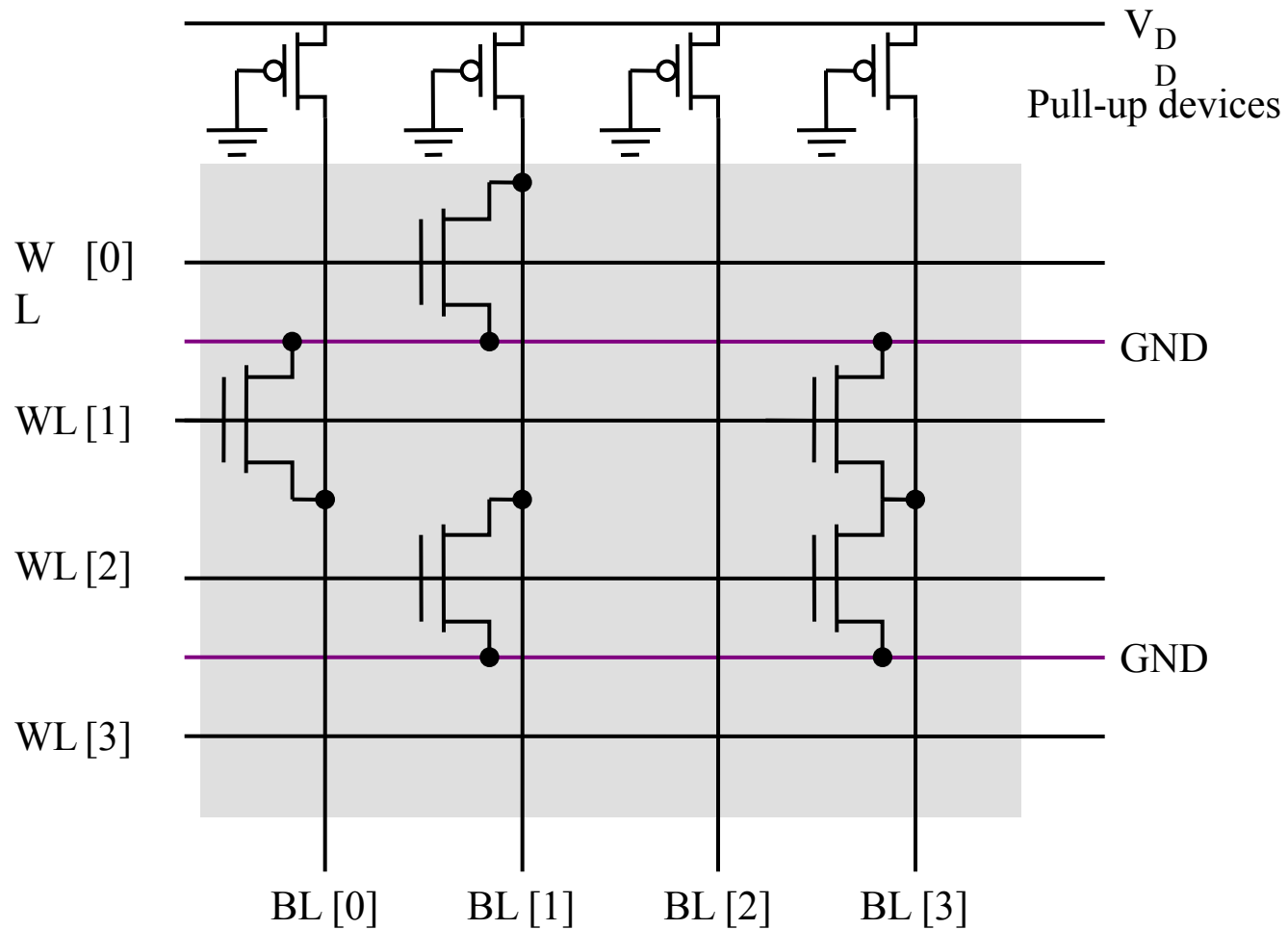
# Nonvolatile Memory

ROM  
PROM  
EPROM

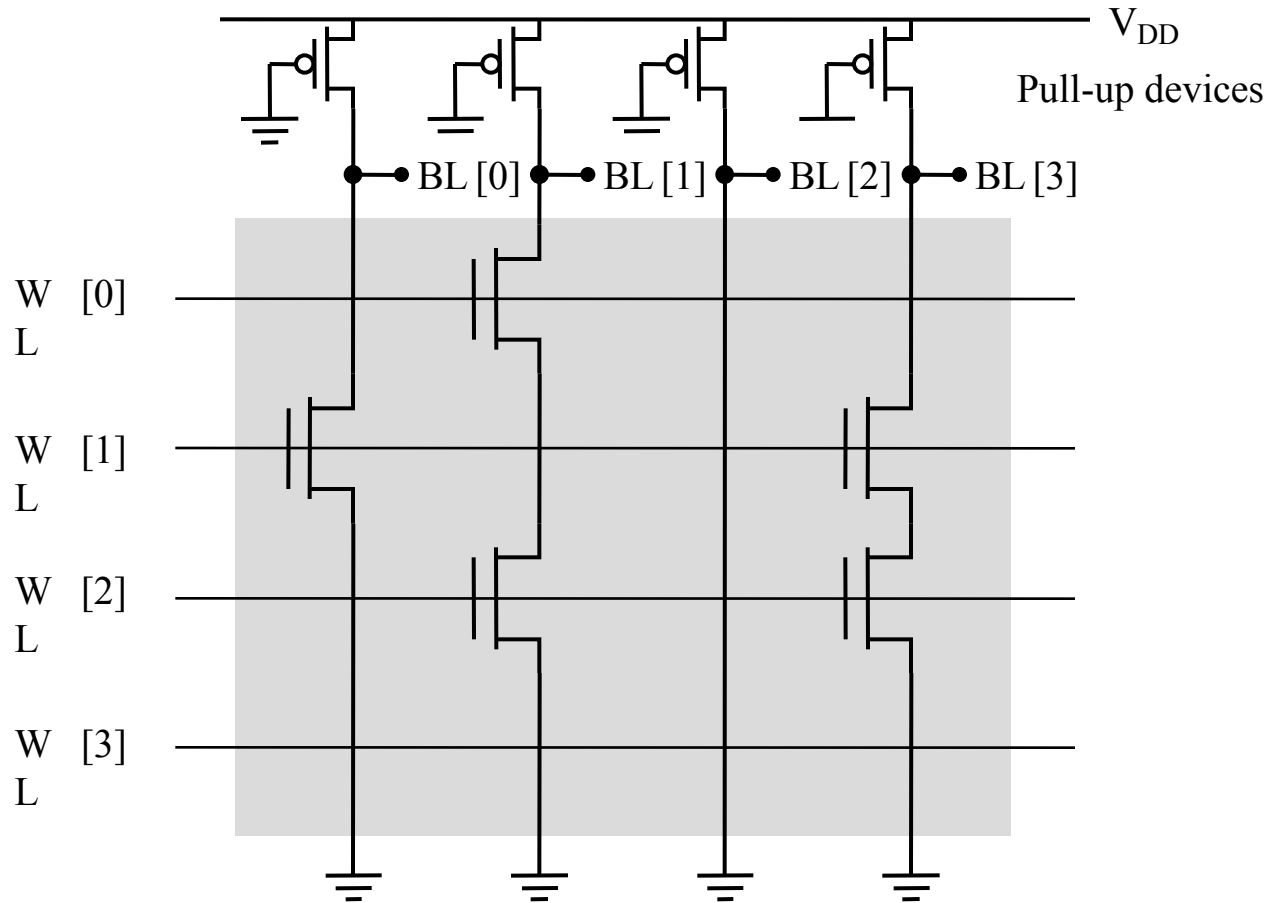


Read-only memory organization, with the fixed contents shown on the right.

# MOS NOR ROM



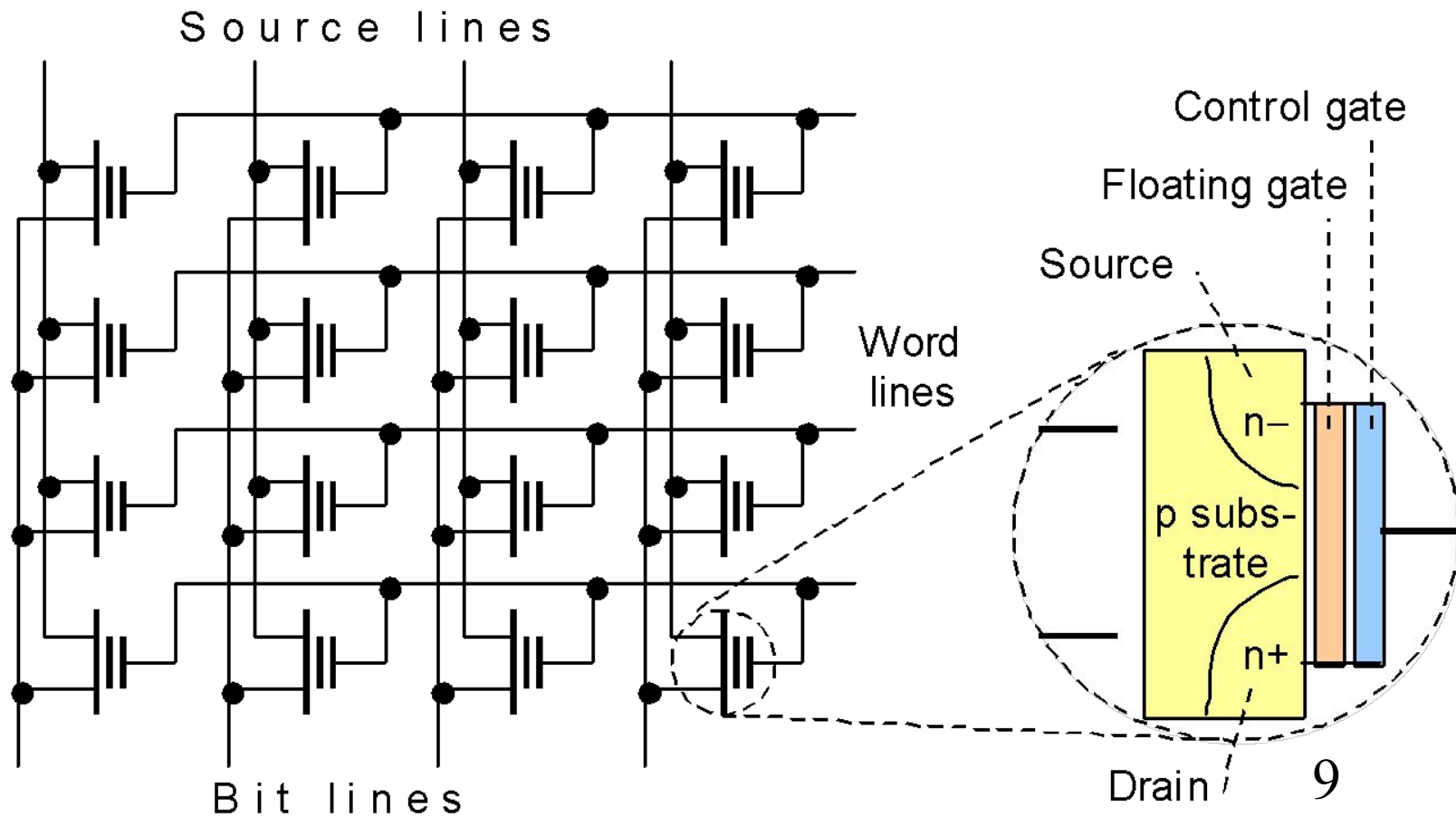
# MOS NAND ROM



All word lines high by default with exception of selected row

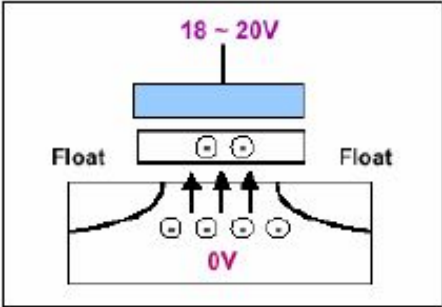
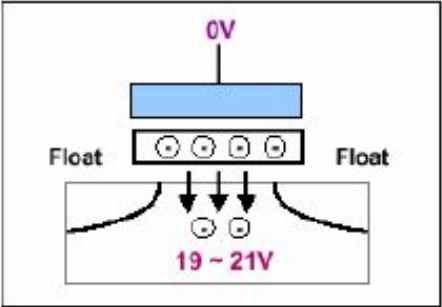


# Flash Memory

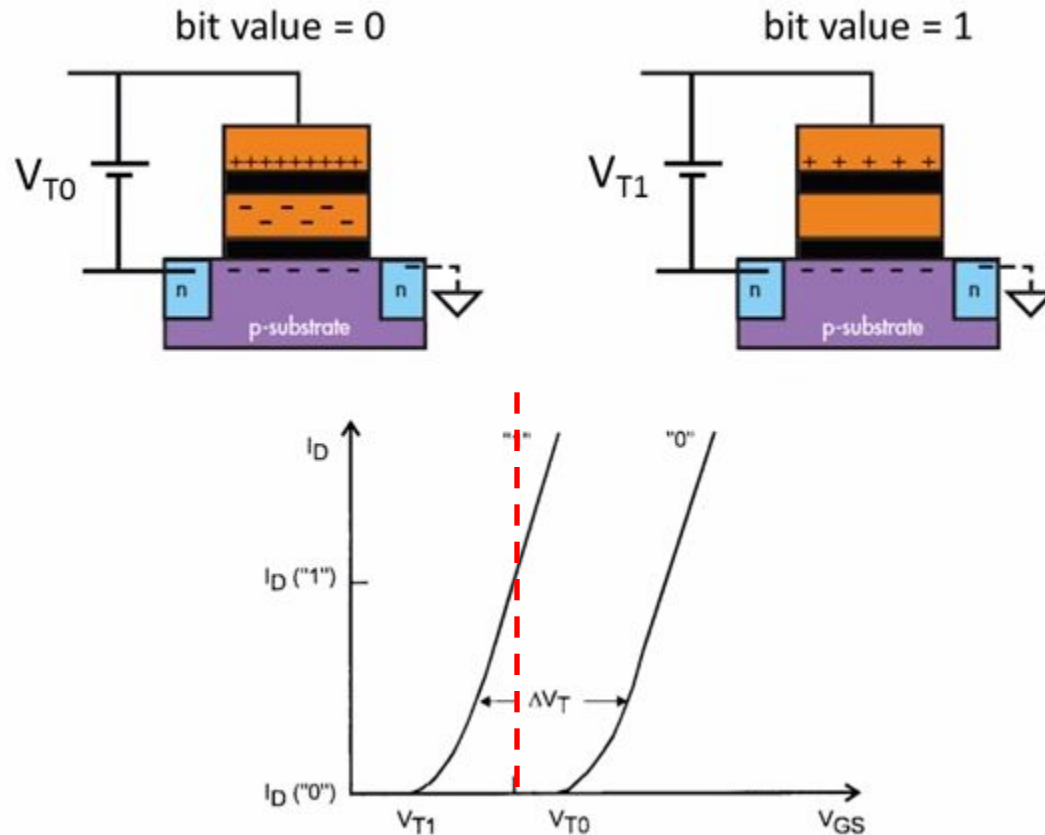


# Flash memory

- Flash memory
  - Non volatile read only memory (ROM)
  - Erase Electrically or UV (EPROM)
  - Uses F-N tunneling for program & erase
  - Reads like DRAM (~ns)
  - Writes like DISK (~ms).

Program	Erase
	
<ul style="list-style-type: none"><li>● Use F-N Tunneling</li><li>● Channel Inversion</li></ul>	<ul style="list-style-type: none"><li>● Use F-N Tunneling</li><li>● Channel Accumulation</li></ul>

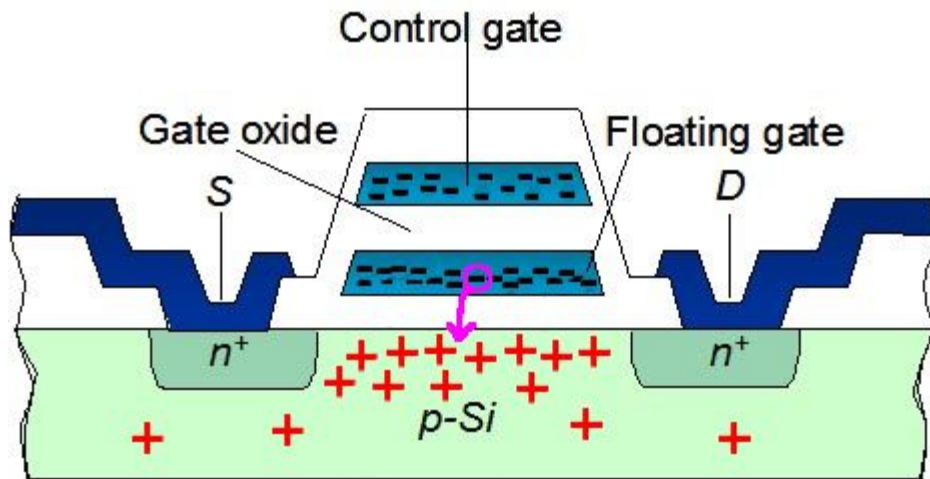
# Reading Memory State



Change in Threshold Voltage due to **Screening Effect** of Floating Gate

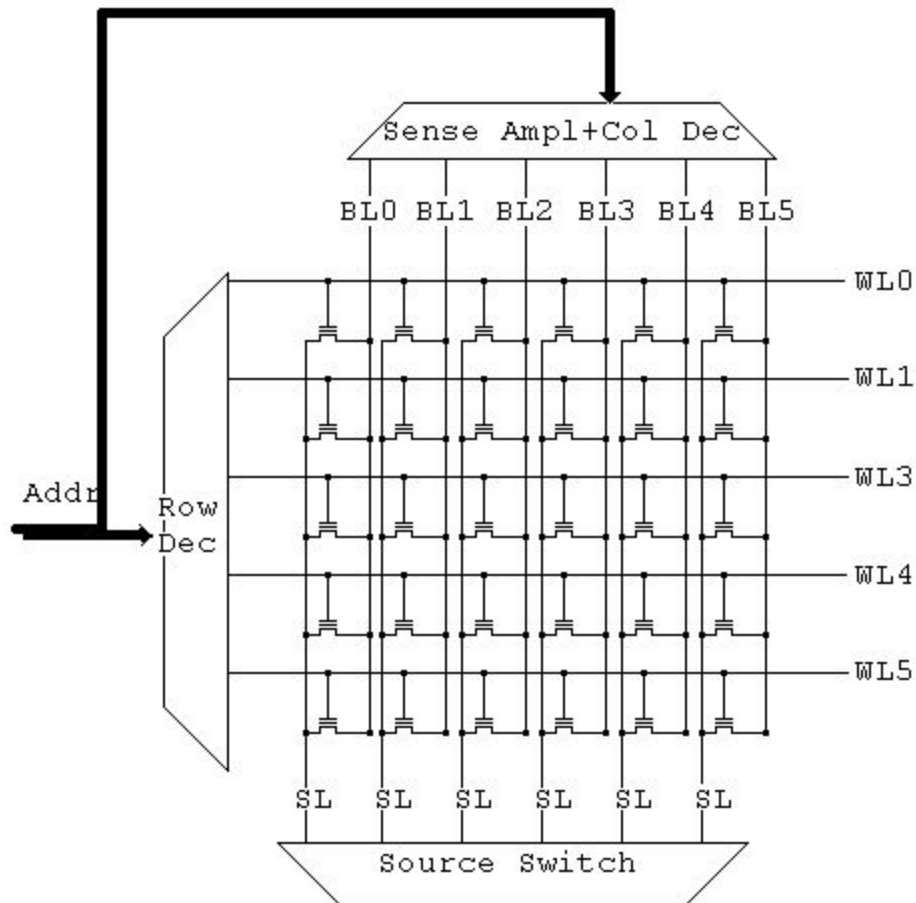
Read mode: Apply intermediate voltage, check whether current is flowing or not

# Writing Memory State



Control gate voltage determines whether electrons are injected to, or push/pulled out of floating gate.

# NOR Array

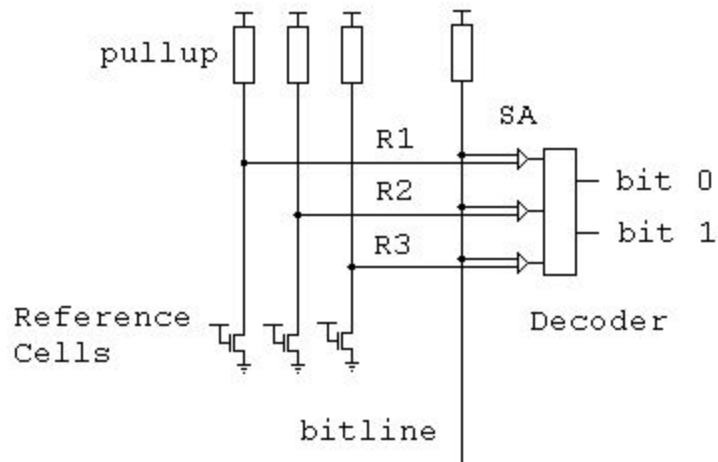


Reading:

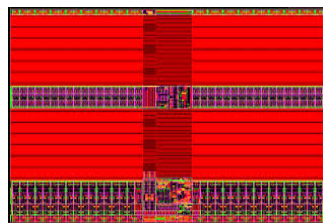
Assert a single word line.  
The source lines are  
asserted and the read of the  
bitline gives the contents of  
the cell.

# Multi-Levels

- By using reference cells set at given levels and comparing them to the value from the bitline, we can determine the value stored.



# Review of memory technologies



Memory type	SRAM	DRAM	Flash
Speed	Very fast	Slow	Slow
Density	Low	High	Very high
Power	High	Low	Very low
Refresh	No	Yes	No
Mechanism	Bi-stable latch	Capacitor	FN tunneling